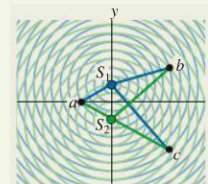




Interference and coherent sources: Monochromatic light is light with a single frequency. Coherence is a definite, unchanging phase relationship between two waves. The overlap of waves from two coherent sources of monochromatic light forms an interference pattern. The principle of superposition states that the total wave disturbance at any point is the sum of the disturbances from the separate waves.



Two-source interference of light: When two sources are in phase, constructive interference occurs where the difference in path length from the two sources is zero or an integer number of wavelengths; destructive interference occurs where the path difference is a half-integer number of wavelengths. If two sources separated by a distance d are both very far from a point P , and the line from the sources to P makes an angle θ with the line perpendicular to the line of the sources, then the condition for constructive interference at P is Eq. (35.4). The condition for destructive interference is Eq. (35.5). When θ is very small, the position y_m of the m th bright fringe on a screen located a distance R from the sources is given by Eq. (35.6). (See Examples 35.1 and 35.2.)

$$d \sin \theta = m\lambda \quad (m = 0, \pm 1, \pm 2, \dots) \quad (35.4)$$

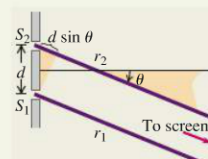
(constructive interference)

$$d \sin \theta = \left(m + \frac{1}{2}\right)\lambda \quad (m = 0, \pm 1, \pm 2, \dots) \quad (35.5)$$

(destructive interference)

$$y_m = R \frac{m\lambda}{d} \quad (35.6)$$

(bright fringes)

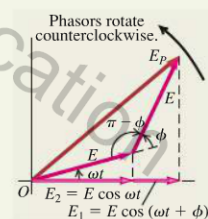


Intensity in interference patterns: When two sinusoidal waves with equal amplitude E and phase difference ϕ are superimposed, the resultant amplitude E_P and intensity I are given by Eqs. (35.7) and (35.10), respectively. If the two sources emit in phase, the phase difference ϕ at a point P (located a distance r_1 from source 1 and a distance r_2 from source 2) is directly proportional to the difference in path length $r_2 - r_1$. (See Example 35.3.)

$$E_P = 2E \left| \cos \frac{\phi}{2} \right| \quad (35.7)$$

$$I = I_0 \cos^2 \frac{\phi}{2} \quad (35.10)$$

$$\phi = \frac{2\pi}{\lambda} (r_2 - r_1) = k(r_2 - r_1) \quad (35.11)$$



Interference in thin films: When light is reflected from both sides of a thin film of thickness t and no phase shift occurs at either surface, constructive interference between the reflected waves occurs when $2t$ is equal to an integral number of wavelengths. If a half-cycle phase shift occurs at one surface, this is the condition for destructive interference. A half-cycle phase shift occurs during reflection whenever the index of refraction in the second material is greater than that in the first. (See Examples 35.4–35.7.)

$$2t = m\lambda \quad (m = 0, 1, 2, \dots) \quad (35.17a)$$

(constructive reflection from thin film, no relative phase shift)

$$2t = \left(m + \frac{1}{2}\right)\lambda \quad (m = 0, 1, 2, \dots) \quad (35.17b)$$

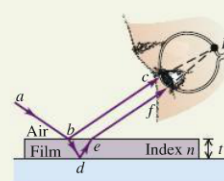
(destructive reflection from thin film, no relative phase shift)

$$2t = \left(m + \frac{1}{2}\right)\lambda \quad (m = 0, 1, 2, \dots) \quad (35.18a)$$

(constructive reflection from thin film, half-cycle relative phase shift)

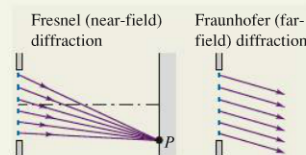
$$2t = m\lambda \quad (m = 0, 1, 2, \dots) \quad (35.18b)$$

(destructive reflection from thin film, half-cycle relative phase shift)





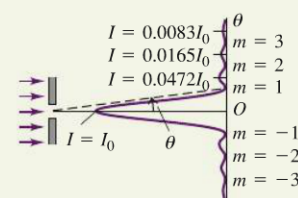
Fresnel and Fraunhofer diffraction: Diffraction occurs when light passes through an aperture or around an edge. When the source and the observer are so far away from the obstructing surface that the outgoing rays can be considered parallel, it is called Fraunhofer diffraction. When the source or the observer is relatively close to the obstructing surface, it is Fresnel diffraction.



Single-slit diffraction: Monochromatic light sent through a narrow slit of width a produces a diffraction pattern on a distant screen. Equation (36.2) gives the condition for destructive interference (a dark fringe) at a point P in the pattern at angle θ . Equation (36.7) gives the intensity in the pattern as a function of θ . (See Examples 36.1–36.3.)

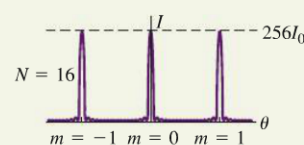
$$\sin \theta = \frac{m\lambda}{a} \quad (m = \pm 1, \pm 2, \dots) \quad (36.2)$$

$$I = I_0 \left\{ \frac{\sin[\pi a(\sin \theta)/\lambda]}{\pi a(\sin \theta)/\lambda} \right\}^2 \quad (36.7)$$



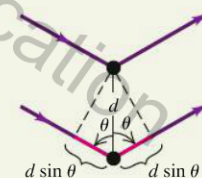
Diffraction gratings: A diffraction grating consists of a large number of thin parallel slits, spaced a distance d apart. The condition for maximum intensity in the interference pattern is the same as for the two-source pattern, but the maxima for the grating are very sharp and narrow. (See Example 36.4.)

$$d \sin \theta = m\lambda \quad (m = 0, \pm 1, \pm 2, \pm 3, \dots) \quad (36.13)$$



X-ray diffraction: A crystal serves as a three-dimensional diffraction grating for x rays with wavelengths of the same order of magnitude as the spacing between atoms in the crystal. For a set of crystal planes spaced a distance d apart, constructive interference occurs when the angles of incidence and scattering (measured from the crystal planes) are equal and when the Bragg condition [Eq. (36.16)] is satisfied. (See Example 36.5.)

$$2d \sin \theta = m\lambda \quad (m = 1, 2, 3, \dots) \quad (36.16)$$



Circular apertures and resolving power: The diffraction pattern from a circular aperture of diameter D consists of a central bright spot, called the Airy disk, and a series of concentric dark and bright rings. Equation (36.17) gives the angular radius θ_1 of the first dark ring, equal to the angular size of the Airy disk. Diffraction sets the ultimate limit on resolution (image sharpness) of optical instruments. According to Rayleigh's criterion, two point objects are just barely resolved when their angular separation θ is given by Eq. (36.17). (See Example 36.6.)

$$\sin \theta_1 = 1.22 \frac{\lambda}{D} \quad (36.17)$$

